

SPIE Photonics West 2019

# Physical-Optics Simulation of Optical Interferometry Systems

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#### Jena, Germany



## **University of Jena**



# **Wyrowski Photonics**



# LightTrans International



## **Optical Design Software and Services**



Hall EF (North) booth 4545-46 German Pavilion



## Make physical optics the platform in optical modeling

# Paradigm Shift in Optical Modeling Needed

• **Status quo:** Ray optics is currently used as the platform in optical modeling. Physical optics "patches" are added where most needed.





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- **Our proposal:** To make physical optics the platform in optical modeling, with ray tracing solidly embedded within.



# Make Physical Optics the Platform in Optical Modeling

- **Status quo:** Ray optics is currently used as the platform in optical modeling. Physical optics "patches" are added where most needed.
- **Our proposal:** To make physical optics the platform in optical modeling, with ray tracing solidly embedded within.

For this paradigm shift physical optics must be **fast** in practice!



# **Fast Electromagnetic Modeling Required**

• Physical optics modeling must be based on solutions of Maxwell's equations.



# **Fast Electromagnetic Modeling Required**

• Physical optics modeling must be based on electromagnetic field solvers.

How to realize a fast electromagnetic modeling in optics?



#### **Field tracing enables fast physical optics**

# **Field Tracing Enables Fast Physical Optics**

#### Field Tracing comprises:

- Application of different electromagnetic field solvers in different regions of one system.
- Interconnection of any type of general and specialized field solver.



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- Interconnection of any type of general and specialized field solver.
- Source mode concept to represent coherent, partially coherent, and incoherent sources.
- ... and many more techniques

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# Physical Optics Enables Theoretically Solid Inclusion of ....

- Investigation of fields in focal regions
- Diffraction at apertures and of light beams
- Vectorial effects and polarization; no paraxial assumption
- Coherence phenomena and source models
- Ultrashort pulse modeling
- Interference and speckles
- Diffraction at gratings and diffractive optical elements
- Scattering effects
- Crystal and metamaterial modeling
- Nano- and microoptics
- Special effects like Gouy phase shift and Goos Hänchen shift
- Nonlinear optics



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- Modern interferometers may use ...
  - ... advanced light sources
  - ... innovative optical components
  - ... different types of detectors
  - ... complex light paths



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# **Field Tracing Enables Fast Physical Optics**

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- Source mode concept to represent coherent, partially coherent, and incoherent sources.
- ... and many more techniques



**Coherence Measurement Using Michelson Interferometer and Fourier Transform Spectroscopy** 

# **Modeling Task**



### **Lateral Interference Fringes – 50nm Bandwidth**



## Lateral Interference Fringes – 100nm Bandwidth



#### **Pointwise Measurement**



### **VirtualLab Fusion Technologies**

![](_page_31_Figure_1.jpeg)

![](_page_31_Figure_2.jpeg)

#### LightTrans International

#### **Fizeau Interferometer for Optical Testing**

# **Modeling Task**

![](_page_33_Figure_1.jpeg)

#### **Tilted Planar Surface under Observation**

![](_page_34_Figure_1.jpeg)

## **Cylindrical Surface under Observation**

![](_page_35_Figure_1.jpeg)

1.86

0.93

### **Spherical Surface under Observation**

![](_page_36_Figure_1.jpeg)

## **VirtualLab Fusion Technologies**

![](_page_37_Figure_1.jpeg)

![](_page_37_Figure_2.jpeg)

#### **Mach-Zehnder Interferometer**

# **Modeling Task**

![](_page_39_Figure_1.jpeg)

#### **Interference Fringe Due to Component Tilt**

![](_page_40_Figure_1.jpeg)

Calculation of interference pattern including element tilt takes less than 2 seconds!

![](_page_40_Figure_3.jpeg)

#### **Interference Fringe Due to Component Shift**

![](_page_41_Figure_1.jpeg)

Calculation of interference pattern including element shift takes less than 2 seconds!

![](_page_41_Figure_3.jpeg)

## **Polarization Interference**

# **Modeling Task**

![](_page_43_Figure_1.jpeg)

## **Interference Pattern Changes with Polarizer Rotation**

![](_page_44_Figure_1.jpeg)

Interference fringes start to disappear, when polarizer rotates from parallel to orthogonal orientation.

![](_page_44_Figure_3.jpeg)

#### **Interference Pattern Changes with Polarizer Rotation**

![](_page_45_Figure_1.jpeg)

![](_page_45_Figure_2.jpeg)

#### **Interference Pattern**

![](_page_46_Figure_1.jpeg)

#### **Examination of Sodium D Lines with Etalon**

# **Modeling Task**

![](_page_48_Figure_1.jpeg)

# **Result: only Transmitted Field**

![](_page_49_Figure_1.jpeg)

## **Result: Transmitted Field + 2 Back Reflections**

![](_page_50_Figure_1.jpeg)

## **Result: Transmitted Field + 4 Back Reflections**

![](_page_51_Figure_1.jpeg)

## **Result: Transmitted Field + 6 Back Reflections**

![](_page_52_Figure_1.jpeg)

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## **Result: Transmitted Field + 18 Back Reflections**

![](_page_53_Figure_1.jpeg)

#### LightTrans International

#### **Result: HR-Coating Reflectance vs. Finesse**

#### Coating **R = 60%** @ 589nm

31: 589	nm R = 60%		-
Light View	Data View		
mm 5.0001749526 mm	C		
-5.0001749526	5.0001749525 mm	4.9647124407 mm	
Light View		Zoom: 0.23837700761	-

#### Coating **R = 80%** @ 589nm

![](_page_54_Picture_4.jpeg)

#### Coating **R = 90%** @ 589nm

![](_page_54_Picture_6.jpeg)

#### **Result: HR-Coating Reflectance vs. Finesse**

![](_page_55_Figure_1.jpeg)

Extract 1D data along the diagonal line

The higher reflectance, the sharper interference stripe

#### **VirtualLab Technologies**

![](_page_56_Figure_1.jpeg)

![](_page_56_Figure_2.jpeg)

#### **Related Talks and Poster Presentations**

- Talk: How the design concepts of high-NA beam splitters and diffusers, as well as of beam shapers by freeform surfaces are related Time & Location: Wednesday, 6 February | 16:30 – 16:50, Room 210
- Talk: Physical-optics modeling of diffractive/meta-lenses and their design Time & Location: Wednesday, 6 February 2019 | 17:10 – 17:30, Room 210
- **Poster**: Design of single-mode fiber coupling lenses and tolerance analysis Time & Location: Tuesday, 5 February 2019 | 18:00 – 20:00, Golden Gate Ballroom
- Poster: Design and optimization strategy of incoupling gratings for near-eye displays
  Time & Location: Wednesday, 6 February 2010 | 18:00 20:00, Goldon Cate Ballroom

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# **Workshops and Seminars**

- SPIE Industry Workshop in cooperation with ZEMAX/OpticStudio<sup>®</sup>
   Modeling and design of diffractive and meta-lenses with VirtualLab Fusion
   Time & Location: Wednesday, 6 February 2019 | 15:30 17:00, Room 12
- Free VirtualLab Fusion Seminar Thursday VirtualLab Fusion Technology and Applications: Interferometry, Microscopy and Fiber Coupling Time & Location: Thursday, 7 February 2019 | 09:00 – 13:00, 49 Geary Street
- Free VirtualLab Fusion Seminar Friday
   Beyond Ray Tracing: Innovative Optical Design with Fast Physical Optics
   Time & Location: Friday, 8 February 2019 | 09:00 16:00, 49 Geary Street